





SN74AXC2T45

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## SN74AXC2T45 2-Bit Translating Transceiver with Configurable Level-Shifting

#### 1 Features

- AEC-Q100 automotive qualified
- Fully configurable dual-rail design allows each port to operate with a power supply range from 0.65V to 3.6V
- Operating temperature from -40°C to +125°C
- Glitch-free power supply sequencing
- Up to 380Mbps support when translating from 1.8V to 3.3V
- V<sub>CC</sub> isolation feature
  - If either V<sub>CC</sub> input is below 100mV, all I/Os outputs are disabled and become highimpedance
- I<sub>off</sub> supports partial-power-down mode operation
- Compatible with AVC family level shifters
- Latch-up performance exceeds 100mA per JESD 78, Class II
- ESD protection exceeds JESD 22
  - 8000-V human-body model
  - 1000-V charged-device model

### 2 Applications

- Enterprise and communications
- Industrial
- Personal electronics
- Wireless infrastructure
- **Building automation**
- Point-of-sale

### 3 Description

The SN74AXC2T45 is a two-bit noninverting bus transceiver that uses two individually configurable power-supply rails. The device is operational with both  $V_{CCA}$  and  $V_{CCB}$  supplies as low as 0.65V. The A port is designed to track V<sub>CCA</sub>, which accepts any supply voltage from 0.65V to 3.6V. The B port is designed to track V<sub>CCB</sub>, which also accepts any supply voltage from 0.65V to 3.6V. Additionally the SN74AXC2T45 is compatible with a single-supply system.

The SN74AXC2T45 device is designed asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level of the direction-control input (DIR). The SN74AXC2T45 device is designed so the control pin (DIR) is referenced to V<sub>CCA</sub>.

This device is fully specified for partial-power-down applications using the  $I_{\text{off}}$  current. The  $I_{\text{off}}$  protection circuitry is designed so that no excessive current is drawn from or to an input, output, or combined I/O that is biased to a specific voltage while the device is powered down.

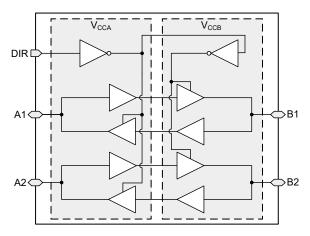
The V<sub>CC</sub> isolation feature is designed so that if either V<sub>CCA</sub> or V<sub>CCB</sub> is less than 100mV, both I/O ports enter a high-impedance state by disabling their outputs.

Glitch-free power supply sequencing allows either supply rail to be powered on or off in any order while providing robust power sequencing performance.

#### **Package Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE <sup>(2)</sup>
	DCT (SSOP, 8)	2.95mm × 4mm
SN74AXC2T45	DCU (VSSOP, 8)	2mm × 3.1mm
	DTM (X2SON, 8)	0.8mm × 1.35mm

- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



**Functional Block Diagram** 



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## **4 Pin Configuration and Functions**



Figure 4-1. DCT Package, 8-Pin SSOP (Top View) Figure 4-2. DCU Package, 8-Pin VSSOP (Top View)

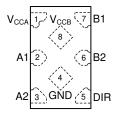


Figure 4-3. DTM Package, 8-Pin X2SON Transparent (Top View)

### **Table 4-1. Pin Functions**

	PIN	TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.	ITPE\''	DESCRIPTION
A1	2	I/O	Input/output A1. Referenced to V <sub>CCA</sub> .
A2	3	I/O	Input/output A2. Referenced to V <sub>CCA</sub> .
B1	7	Input/output B1. Referenced to V <sub>CCB</sub> .	
B2	6	I/O	Input/output B2. Referenced to V <sub>CCB</sub> .
DIR	5		Direction-control in for both ports. Referenced to V <sub>CCA</sub>
GND	4	G	Ground
V <sub>CCA</sub> 1 P A-port power sup			A-port power supply voltage. 0.65V ≤ V <sub>CCA</sub> ≤ 3.6V
V <sub>CCB</sub>	8	Р	B-port power supply voltage. 0.65V ≤ V <sub>CCB</sub> ≤ 3.6V

(1) I = input, O = output, P = power, G = ground



### **5 Specifications**

## 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNITS
$V_{CCA}$	Supply voltage A		-0.5	4.2	V
$V_{CCB}$	Supply voltage B		-0.5	4.2	V
		I/O Ports (A Port)	-0.5	4.2	
$V_{I}$	Input Voltage <sup>(2)</sup>	I/O Ports (B Port)	-0.5	4.2	V
		Control Inputs	-0.5	4.2	
.,	Value and the state of the stat	A Port	-0.5	4.2	.,
Vo	Voltage applied to any output in the high-impedance or power-off state <sup>(2)</sup>	B Port	-0.5	4.2	V
\ /	Voltage and in the annual track in the birth and an extend (2) (3)	A Port	-0.5	V <sub>CCA</sub> + 0.2	V
Vo	Voltage applied to any output in the high or low state <sup>(2) (3)</sup>	B Port	-0.5	V <sub>CCB</sub> + 0.2	\ \ \
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0	-50		mA
lok	Output clamp current	V <sub>O</sub> < 0	-50		mA
Io	Continuous output current		-50	50	mA
	Continuous current through V <sub>CC</sub> or GND		-100	100	mA
Tj	Junction Temperature			150	°C
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input voltage and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The output positive-voltage rating may be exceeded up to 4.2V maximum if the output current rating is observed.

### 5.2 ESD Ratings

				VALUE	UNIT
	·	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±8000	\/
Ľ	(ESD)	Liectiostatic discharge	Charged device model (CDM), per JEDEC V Specification JESD22-C101 <sup>(2)</sup>	±1000	v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



## 5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1) 2

				MIN	MAX	UNIT
V <sub>CCA</sub>	Supply voltage A			0.65	3.6	V
V <sub>CCB</sub>	Supply voltage B			0.65	3.6	V
			V <sub>CCI</sub> = 0.65V - 0.75V	V <sub>CCI</sub> × 0.70		
			V <sub>CCI</sub> = 0.76V - 1V	V <sub>CCI</sub> × 0.70		
		Data Inputs	V <sub>CCI</sub> = 1.1V – 1.95V	V <sub>CCI</sub> × 0.65		
			V <sub>CCI</sub> = 2.3V – 2.7V	1.6		
.,	High lavel in a strongles as		V <sub>CCI</sub> = 3V – 3.6V	2		
$V_{IH}$	High-level input voltage		$V_{CCA} = 0.65V - 0.75V$	V <sub>CCA</sub> × 0.70		
			V <sub>CCA</sub> = 0.76V – 1V	V <sub>CCA</sub> × 0.70		
		Control Input (DIR), Referenced to V <sub>CCA</sub>	V <sub>CCA</sub> = 1.1V – 1.95V	V <sub>CCA</sub> × 0.65		
		TO A CICA	V <sub>CCA</sub> = 2.3V – 2.7V	1.6		
			V <sub>CCA</sub> = 3V – 3.6V	2		
			$V_{CCI} = 0.65V - 0.75V$		V <sub>CCI</sub> x 0.30	
			V <sub>CCI</sub> = 0.76V – 1V		V <sub>CCI</sub> x 0.30	
		Data Inputs	V <sub>CCI</sub> = 1.1V – 1.95V		V <sub>CCI</sub> x 0.35	
			V <sub>CCI</sub> = 2.3V – 2.7V		0.7	
V	Low lovel input veltage		V <sub>CCI</sub> = 3V – 3.6V		0.8	V
$V_{IL}$	Low-level input voltage		$V_{CCA} = 0.65V - 0.75V$		V <sub>CCA</sub> × 0.30	V
			V <sub>CCA</sub> = 0.76V – 1V		V <sub>CCA</sub> × 0.30	
		Control Input (DIR), Referenced to V <sub>CCA</sub>	V <sub>CCA</sub> = 1.1V – 1.95V		V <sub>CCA</sub> × 0.35	
		LO V CCA	V <sub>CCA</sub> = 2.3V – 2.7V		0.7	
			V <sub>CCA</sub> = 3V – 3.6V		0.8	
VI	Input voltage			0	3.6	V
\/	Output voltage	Active State		0	V <sub>CCO</sub>	V
Vo	Output voltage	Tri-State		0	3.6	V
Δt/Δv <sup>2</sup>	Input transition rise and	fall time			10	ns/V
Δt/Δv <sup>3</sup>	Single channel input trar	sition rise and fall time			100	ns/V
T <sub>A</sub>	Operating free-air tempe	rature		-40	125	°C

<sup>(1)</sup> 

### **5.4 Thermal Information**

	TUEDNAL METDIO (1)		SN74AXC2T45		
	THERMAL METRIC (1)	DCT (SM8)	DCU (VSSOP)	DTM (X2SON)	UNIT
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	223.5	242.9	225.9	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	120.7	96.2	131.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	138.0	153.3	141.3	°C/W
Y <sub>JT</sub>	Junction-to-top characterization parameter	47.5	38.2	12.7	°C/W
Y <sub>JB</sub>	Junction-to-board characterization parameter	136.7	152.5	140.9	°C/W

(1) For more information about thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

 $V_{CCI}$  is the  $V_{CC}$  associated with the input port.  $V_{CCO}$  is the  $V_{CC}$  associated with the output port. All unused inputs of the device must be held at  $V_{CC}$  or GND for proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.

Input transition rate of a single channel while the other channels are at a valid logic state and not switching.



### 5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted) (1) (2) (3)

						Оре	erating free-a	ir temper	ature (T <sub>A</sub>	)	
PA	RAMETER	TEST	CONDITIONS	V <sub>CCA</sub>	V <sub>CCB</sub>	-40°	C to 85°C	-40°	C to 125°	,C	UNIT
						MIN	TYP MA	X MIN	TYP	MAX	
			I <sub>OH</sub> = -100μA	0.7V - 3.6V	0.7V - 3.6V	V <sub>CCO</sub> -0.1		V <sub>CCO</sub> -0.1			
			I <sub>OH</sub> = -50μA	0.65V	0.65V	0.55		0.55			
			I <sub>OH</sub> = -200μA	0.76V	0.76V	0.58		0.58			
	High-level		I <sub>OH</sub> = -500μA	0.85V	0.85V	0.65		0.65			
/ <sub>OH</sub>	output voltage	$V_I = V_{IH}$	I <sub>OH</sub> = -3mA	1.1V	1.1V	0.85		0.85			V
			I <sub>OH</sub> = -6mA	1.4V	1.4V	1.05		1.05			
			I <sub>OH</sub> = -8mA	1.65V	1.65V	1.2		1.2			
			I <sub>OH</sub> = -9mA	2.3V	2.3V	1.75		1.75			
			I <sub>OH</sub> = -12mA	3V	3V	2.3		2.3			
			I <sub>OL</sub> = 100μA	0.7V - 3.6V	0.7V - 3.6V		0.	1		0.1	
			I <sub>OL</sub> = 50μA	0.65V	0.65V		0.	1		0.1	
			I <sub>OL</sub> = 200μA	0.76V	0.76V		0.1	8		0.18	
			I <sub>OL</sub> = 500μA	0.85V	0.85V		0.	2		0.2	
/ <sub>OL</sub>	Low-level output voltage	V <sub>I</sub> = V <sub>IL</sub>	I <sub>OL</sub> = 3mA	1.1V	1.1V		0.2	5		0.25	V
	surput tellings		I <sub>OL</sub> = 6mA	1.4V	1.4V		0.3	5		0.35	
			I <sub>OL</sub> = 8mA	1.65V	1.65V		0.4	5		0.45	
			I <sub>OL</sub> = 9mA	2.3V	2.3V		0.5	5		0.55	
			I <sub>OL</sub> = 12mA	3V	3V		0.	7		0.7	
	Input leakage	Control in V <sub>CCA</sub> or 0	nput (DIR):V <sub>I</sub> = GND	0.65V - 3.6V	0.65V - 3.6V	-0.5	0.	5 -1		1	μΑ
1	current	Data Inpo	uts (Ax, Bx),V <sub>I</sub> = GND	0.65V - 3.6V	0.65V - 3.6V	-4		4 -8		8	μA
off	Partial power	A Port: V 3.6V	$I_1$ or $V_0 = 0V -$	0V	0V - 3.6V	-4		4 -8		8	μA
οπ	down current	B Port: V 3.6V	or V <sub>O</sub> = 0V –	0V – 3.6V	0V	-4		4 -8		8	μ,
	V gunnhy	V <sub>1</sub> =		0.65V - 3.6V	0.65V - 3.6V			8		14	
CCA	V <sub>CCA</sub> supply current	V <sub>CCI</sub> or	I <sub>O</sub> = 0	0V	3.6V	-2		-12			μΑ
		GND		3.6V	0V			4		8	
	V summb	V <sub>1</sub> =		0.65V - 3.6V	0.65V - 3.6V			8		14	
ССВ	V <sub>CCB</sub> supply current	V <sub>CCI</sub> or	I <sub>O</sub> = 0	0V	3.6V			4		8	μΑ
		GND		3.6V	0V	-2		-12			
CCA +	Combined supply current	V <sub>I</sub> = V <sub>CCI</sub> or GND	I <sub>O</sub> = 0	0.65V - 3.6V	0.65V - 3.6V		1	6		23	μA
Ç <sub>i</sub>	Control Input (DIR) Capacitance	V <sub>I</sub> = 3.3V	or GND	3.3V	3.3V		3.3		3.3		pF
S <sub>io</sub>	Data I/O Capacitance		5V DC +1MHz sine wave	3.3V	3.3V		5.4		5.4		pF

 $V_{CCI}$  is the  $V_{CC}$  associated with the input port.  $V_{CCO}$  is the  $V_{CC}$  associated with the output port. All typical data is taken at 25°C. (1) (2)



## 5.6 Switching Characteristics, $V_{CCA} = 0.7 \pm 0.05V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V <sub>CCB</sub> )							
P.	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	170	0.5	115	0.5	84	0.5	50	0.5	50	0.5	56	0.5	71	0.5	106	
	Propagation			-40°C to 125°C	0.5	170	0.5	115	0.5	84	0.5	50	0.5	50	0.5	56	0.5	71	0.5	106	ns
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	170	0.5	149	0.5	122	0.5	83	0.5	79	0.5	78	0.5	77	0.5	76	
			^	-40°C to 125°C	0.5	170	0.5	149	0.5	122	0.5	83	0.5	79	0.5	78	0.5	77	0.5	76	
		DIR	Α	-40°C to 85°C	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	
t <sub>dis</sub>	Disable time	DIK	^	-40°C to 125°C	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	0.5	140	ns
<sup>L</sup> dis	Disable time	DIR	В	-40°C to 85°C	0.5	143	0.5	105	0.5	84	0.5	41	0.5	39	0.5	42	0.5	56	0.5	107	115
		DIK	Ь	-40°C to 125°C	0.5	143	0.5	105	0.5	84	0.5	41	0.5	39	0.5	42	0.5	56	0.5	107	
		DIR	Α	-40°C to 85°C	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	
	Enable time	DIK	A	-40°C to 125°C	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	0.5	311	no
t <sub>en</sub>	Lilable tille	DIR	В	-40°C to 85°C	0.5	306	0.5	247	0.5	216	0.5	186	0.5	182	0.5	183	0.5	194	0.5	228	ns
		אוט	D	-40°C to 125°C	0.5	306	0.5	247	0.5	216	0.5	186	0.5	182	0.5	183	0.5	194	0.5	228	



## 5.7 Switching Characteristics, $V_{CCA} = 0.8 \pm 0.04V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V <sub>CCB</sub> )																
F	PARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT									
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX										
		Α	В	-40°C to 85°C	0.5	150	0.5	94	0.5	63	0.5	33	0.5	28	0.5	27	0.5	28	0.5	34										
	Propagation	A	В	-40°C to 125°C	0.5	150	0.5	94	0.5	63	0.5	33	0.5	28	0.5	27	0.5	28	0.5	34	no									
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	115	0.5	94	0.5	76	0.5	50	0.5	41	0.5	40	0.5	38	0.5	38	ns									
				-40°C to 125°C	0.5	115	0.5	94	0.5	76	0.5	50	0.5	41	0.5	40	0.5	38	0.5	38										
		DIR	Α	-40°C to 85°C	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96										
	Disable time	DIK	A	-40°C to 125°C	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	0.5	96	no									
t <sub>dis</sub>	Disable time	DIR	В	-40°C to 85°C	0.5	136	0.5	97	0.5	76	0.5	33	0.5	27	0.5	26	0.5	28	0.5	35	ns									
		DIIX		-40°C to 125°C	0.5	136	0.5	97	0.5	76	0.5	33	0.5	27	0.5	26	0.5	28	0.5	35										
		DIR	Α	-40°C to 85°C	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246										
t <sub>en</sub>	Enable time	DIK	A	-40°C to 125°C	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246	0.5	246										
(1)	LIMDIE UITIE		DID	DIB 5	DIR R	DIR B	DIB I	DIB	DIP	DIB	DIB	B	-40°C to 85°C	0.5	243	0.5	188	0.5	157	0.5	128	0.5	123	0.5	122	0.5	123	0.5	125	ns
		DIR	٥	-40°C to 125°C	0.5	243	0.5	188	0.5	157	0.5	128	0.5	123	0.5	122	0.5	123	0.5	125										

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.



## 5.8 Switching Characteristics, $V_{CCA} = 0.9 \pm 0.045V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

											B-Port S	Supply	Voltage	(V <sub>CCB</sub> )							
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	).04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	122	0.5	76	0.5	51	0.5	23	0.5	18	0.5	16	0.5	15	0.5	17	
	Propagation			-40°C to 125°C	0.5	122	0.5	76	0.5	51	0.5	23	0.5	18	0.5	16	0.5	15	0.5	17	ne
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	84	0.5	63	0.5	51	0.5	39	0.5	28	0.5	24	0.5	21	0.5	21	ns
			^	-40°C to 125°C	0.5	84	0.5	63	0.5	51	0.5	39	0.5	28	0.5	24	0.5	21	0.5	21	
		DIR	Α	-40°C to 85°C	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	
<b>.</b>	Disable time	DIK	^	-40°C to 125°C	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	0.5	74	1 1
t <sub>dis</sub>	Disable time	DIR	В	-40°C to 85°C	0.5	133	0.5	94	0.5	73	0.5	30	0.5	23	0.5	22	0.5	20	0.5	22	ns
		DIIX		-40°C to 125°C	0.5	133	0.5	94	0.5	73	0.5	31	0.5	24	0.5	22	0.5	20	0.5	23	
		DIR	Α	-40°C to 85°C	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	
t <sub>en</sub>	Enable time	DIK	^	-40°C to 125°C	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	0.5	211	ne
(1)	Lilable tille	DIR	В	-40°C to 85°C	0.5	192	0.5	146	0.5	120	0.5	93	0.5	88	0.5	86	0.5	85	0.5	87	ns
		חות	B	-40°C to 125°C	0.5	192	0.5	146	0.5	120	0.5	93	0.5	88	0.5	86	0.5	85	0.5	87	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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## 5.9 Switching Characteristics, $V_{CCA} = 1.2 \pm 0.1V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

											B-Port S	upply	Voltage	(V <sub>CCB</sub> )							
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	84	0.5	51	0.5	38	0.5	15	0.5	10	0.5	9	0.5	7	0.5	8	
	Propagation	^	В	-40°C to 125°C	0.5	84	0.5	51	0.5	38	0.5	15	0.5	11	0.5	9	0.5	8	0.5	8	
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	50	0.5	33	0.5	23	0.5	15	0.5	12	0.5	10	0.5	8	0.5	7	ns
			^	-40°C to 125°C	0.5	50	0.5	33	0.5	23	0.5	15	0.5	12	0.5	10	0.5	8	0.5	7	
		DIR	Α	-40°C to 85°C	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	0.5	26	
	Disable time	DIK	A	-40°C to 125°C	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	0.5	27	
t <sub>dis</sub>	Disable time	DIR	В	-40°C to 85°C	0.5	129	0.5	90	0.5	70	0.5	27	0.5	20	0.5	18	0.5	15	0.5	15	ns
		DIIX		-40°C to 125°C	0.5	129	0.5	90	0.5	71	0.5	28	0.5	21	0.5	19	0.5	16	0.5	16	
		DIR	Α	-40°C to 85°C	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	
t <sub>en</sub>	Enable time	DIK	A	-40°C to 125°C	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	0.5	177	
(1)	Enable time	DIB	В	-40°C to 85°C	0.5	105	0.5	71	0.5	59	0.5	40	0.5	36	0.5	35	0.5	33	0.5	34	ns
		DIR	В	-40°C to 125°C	0.5	105	0.5	71	0.5	59	0.5	41	0.5	37	0.5	36	0.5	34	0.5	35	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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## 5.10 Switching Characteristics, $V_{CCA} = 1.5 \pm 0.1V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

										ı	B-Port S	Supply	Voltage	(V <sub>CCB</sub> )							
	PARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	79	0.5	41	0.5	28	0.5	12	0.5	9	0.5	7	0.5	6	0.5	6	
	Propagation			-40°C to 125°C	0.5	79	0.5	41	0.5	28	0.5	12	0.5	9	0.5	8	0.5	6	0.5	6	1 1
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	50	0.5	28	0.5	18	0.5	10	0.5	9	0.5	8	0.5	6	0.5	5	ns
				-40°C to 125°C	0.5	50	0.5	28	0.5	18	0.5	11	0.5	9	0.5	8	0.5	6	0.5	5	
		DIR	Α	-40°C to 85°C	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	0.5	18	
t <sub>dis</sub>	Disable time	DIK		-40°C to 125°C	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	0.5	19	ns
<sup>L</sup> dis	Disable time	DIR	В	-40°C to 85°C	0.5	128	0.5	89	0.5	69	0.5	26	0.5	19	0.5	17	0.5	13	0.5	13	] 115
		Diix		-40°C to 125°C	0.5	128	0.5	89	0.5	70	0.5	27	0.5	20	0.5	18	0.5	14	0.5	14	
		DIR	A	-40°C to 85°C	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	
t <sub>en</sub>	Enable time	DIK		-40°C to 125°C	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	0.5	172	ne
(1)	Lilable tille	DIR	В	-40°C to 85°C	0.5	92	0.5	54	0.5	42	0.5	31	0.5	27	0.5	25	0.5	24	0.5	24	ns
		DIIX		-40°C to 125°C	0.5	92	0.5	54	0.5	42	0.5	31	0.5	28	0.5	26	0.5	25	0.5	25	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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## 5.11 Switching Characteristics, $V_{CCA} = 1.8 \pm 0.15V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

	-										B-Port S	upply	Voltage	(V <sub>CCB</sub> )							
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ± (	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	78	0.5	40	0.5	24	0.5	10	0.5	8	0.5	7	0.5	5	0.5	5	
	Propagation	A	В	-40°C to 125°C	0.5	78	0.5	40	0.5	24	0.5	10	0.5	8	0.5	7	0.5	6	0.5	5	no
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	56	0.5	27	0.5	16	0.5	9	0.5	7	0.5	7	0.5	5	0.5	4	ns
			^	-40°C to 125°C	0.5	56	0.5	27	0.5	16	0.5	9	0.5	8	0.5	7	0.5	5	0.5	5	
		DIR	Α	-40°C to 85°C	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	0.5	16	
	Disable time	DIK	A	-40°C to 125°C	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	0.5	17	no
t <sub>dis</sub>	Disable time	DIR	В	-40°C to 85°C	0.5	127	0.5	88	0.5	69	0.5	25	0.5	18	0.5	16	0.5	12	0.5	12	ns
		DIIX		-40°C to 125°C	0.5	127	0.5	88	0.5	70	0.5	26	0.5	19	0.5	17	0.5	13	0.5	13	
		DIR	Α	-40°C to 85°C	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	
t <sub>en</sub>	Enable time	DIK	A	-40°C to 125°C	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	0.5	171	ne
(1)	Lilable tille	DIR	В	-40°C to 85°C	0.5	89	0.5	50	0.5	36	0.5	26	0.5	23	0.5	22	0.5	21	0.5	20	ns
		DIIX	5	-40°C to 125°C	0.5	89	0.5	50	0.5	36	0.5	27	0.5	24	0.5	23	0.5	22	0.5	21	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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## 5.12 Switching Characteristics, $V_{CCA} = 2.5 \pm 0.2V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

											B-Port S	Supply	Voltage	(V <sub>CCB</sub> )							
	PARAMETER	FROM	то	Test Conditions	0.7 ± 0	).05V	0.8 ± 0	.04V	0.9 ± 0	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	).15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	77	0.5	38	0.5	21	0.5	8	0.5	6	0.5	5	0.5	5	0.5	4	
	Propagation			-40°C to 125°C	0.5	77	0.5	38	0.5	21	0.5	8	0.5	6	0.5	5	0.5	5	0.5	5	ne
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	71	0.5	28	0.5	15	0.5	7	0.5	6	0.5	5	0.5	5	0.5	4	ns
			^	-40°C to 125°C	0.5	71	0.5	28	0.5	15	0.5	8	0.5	6	0.5	6	0.5	5	0.5	4	
		DIR	Α	-40°C to 85°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	
t <sub>dis</sub>	Disable time	DIK	^	-40°C to 125°C	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	0.5	12	ns
<sup>L</sup> dis	Disable time	DIR	В	-40°C to 85°C	0.5	127	0.5	88	0.5	68	0.5	25	0.5	18	0.5	15	0.5	12	0.5	11	] 115
		DIIX		-40°C to 125°C	0.5	127	0.5	88	0.5	69	0.5	26	0.5	19	0.5	16	0.5	12	0.5	12	
		DIR	Α	-40°C to 85°C	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	
t <sub>en</sub>	Enable time	DIK	A	-40°C to 125°C	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	0.5	182	no
(1)	Lilable tille	DIR	В	-40°C to 85°C	0.5	84	0.5	46	0.5	29	0.5	18	0.5	17	0.5	16	0.5	15	0.5	15	ns
		חות	B	-40°C to 125°C	0.5	84	0.5	46	0.5	29	0.5	19	0.5	18	0.5	17	0.5	16	0.5	16	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

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## 5.13 Switching Characteristics, $V_{CCA} = 3.3 \pm 0.3V$

See Figure 5 and Table 1 for test circuit and loading. See Figure 6, Figure 7, and Figure 8 for measurement waveforms.

	-										B-Port S	upply	Voltage	(V <sub>CCB</sub> )							
F	ARAMETER	FROM	то	Test Conditions	0.7 ± 0	.05V	0.8 ± 0	.04V	0.9 ± 0.	.045V	1.2 ±	0.1V	1.5 ±	0.1V	1.8 ± 0	.15V	2.5 ±	0.2V	3.3 ±	0.3V	UNIT
					MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
		Α	В	-40°C to 85°C	0.5	76	0.5	38	0.5	21	0.5	7	0.5	5	0.5	4	0.5	4	0.5	4	
	Propagation	A	В	-40°C to 125°C	0.5	76	0.5	38	0.5	21	0.5	7	0.5	5	0.5	5	0.5	4	0.5	4	no
t <sub>pd</sub>	delay	В	Α	-40°C to 85°C	0.5	105	0.5	34	0.5	17	0.5	8	0.5	6	0.5	5	0.5	4	0.5	4	ns
			^	-40°C to 125°C	0.5	105	0.5	34	0.5	17	0.5	8	0.5	6	0.5	5	0.5	5	0.5	4	
		DIR	Α	-40°C to 85°C	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	0.5	10	
	Disable time	DIK	A	-40°C to 125°C	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	0.5	11	no
t <sub>dis</sub>	Disable time	DIR	В	-40°C to 85°C	0.5	128	0.5	88	0.5	68	0.5	24	0.5	17	0.5	15	0.5	11	0.5	11	ns
		DIIX		-40°C to 125°C	0.5	128	0.5	88	0.5	69	0.5	26	0.5	19	0.5	16	0.5	12	0.5	11	
		DIR	Α	-40°C to 85°C	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	
t <sub>en</sub>	Enable time	DIK	A	-40°C to 125°C	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	0.5	218	
(1)	Enable time	DIR	В	-40°C to 85°C	0.5	83	0.5	45	0.5	28	0.5	17	0.5	15	0.5	14	0.5	14	0.5	14	ns
		DIIX	5	-40°C to 125°C	0.5	83	0.5	45	0.5	28	0.5	18	0.5	16	0.5	15	0.5	15	0.5	15	

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the Enable Times section.

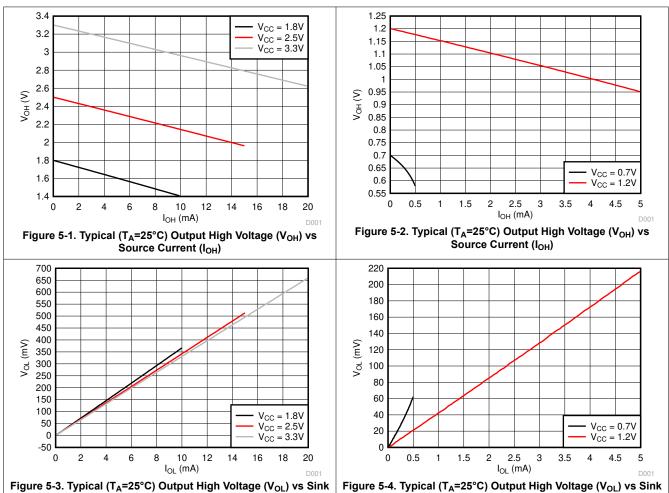
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# 5.14 Operating Characteristics: $T_A = 25$ °C

	PARAMETER	TEST CONDITIONS	V <sub>CCA</sub>	V <sub>CCB</sub>	MIN	TYP	MAX	UNIT
			0.7V	0.7V		2.2		
			0.8V	0.8V		2.0		
			0.9V	0.9V		2.0		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		2.0		pF
	per transceiver (A to B)	1MHz, tr = tf = 1 ns	1.5V	1.5V		2.0		рг
			1.8V	1.8V		2.1		
			2.5V	2.5V		2.5		
			3.3V	3.3V		3.0		
C <sub>pdA</sub>			0.7V	0.7V		10.6		
			0.8V	V8.0		10.7		
			0.9V	0.9V		10.6		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		10.8		nE
	per transceiver (B to A)	1MHz, tr = tf = 1 ns	1.5V	1.5V		11.1		pF
			1.8V	1.8V		12.2		
			2.5V	2.5V		15.9		
			3.3V	3.3V		19.6		
			0.7V	0.7V		10.6		
			0.8V	V8.0		10.7		
			0.9V	0.9V		10.6		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		10.8		nE
	per transceiver (A to B)	1MHz, tr = tf = 1 ns	1.5V	1.5V		11.1		pF
			1.8V	1.8V		12.2		
			2.5V	2.5V		15.8		
C			3.3V	3.3V		19.3		
C <sub>pdB</sub>			0.7V	0.7V		2.2		
			0.8V	0.8V		2.0		
			0.9V	0.9V		2.0		
	Power Dissipation Capacitance	CL = 0, RL = Open f =	1.2V	1.2V		2.0		pF
	per transceiver (B to A)	1MHz, tr = tf = 1 ns	1.5V	1.5V		2.0		ρı
			1.8V	1.8V		2.1		
			2.5V	2.5V		2.5		
			3.3V	3.3V		3.0		

### 5.15 Typical Characteristics



Current (I<sub>OL</sub>)

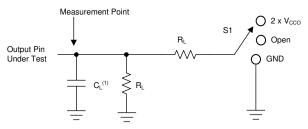


### **6 Parameter Measurement Information**

### 6.1 Load Circuit and Voltage Waveforms

Unless otherwise noted, all input pulses are supplied by generators having the following characteristics:

- f = 1MHz
- $Z_O = 50\Omega$
- dv/dt ≤ 1 ns/V

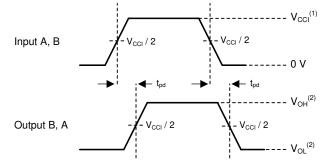


A. C<sub>L</sub> includes probe and jig capacitance.

Figure 6-1. Load Circuit

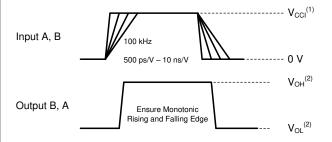
**Table 6-1. Load Circuit Conditions** 

	Parameter	V <sub>cco</sub>	R <sub>L</sub>	CL	S <sub>1</sub>	V <sub>TP</sub>
Δt/Δν	Input transition rise or fall rate	0.65V - 3.6V	1ΜΩ	15pF	Open	N/A
	Propagation (delay) time	1.1V – 3.6V	2kΩ	15pF	Open	N/A
t <sub>pd</sub>	Propagation (delay) time	0.65V - 0.95V	20kΩ	15pF	Open	N/A
		3V – 3.6V	2kΩ	15pF	2 × V <sub>CCO</sub>	0.3V
	Enable time disable time	1.65V – 2.7V	2kΩ	15pF	2 × V <sub>CCO</sub>	0.15V
len, ldis	Enable time, disable time	1.1V – 1.6V	2kΩ	15pF	2 × V <sub>CCO</sub>	0.1V
		0.65V - 0.95V	20kΩ	15pF	2 × V <sub>CCO</sub>	0.1V
		3V – 3.6V	2kΩ	15pF	GND	0.3V
	Fueble time disable time	1.65V – 2.7V	2kΩ	15pF	GND	0.15V
len, ldis	Enable time, disable time	1.1V – 1.6V	2kΩ	15pF	GND	0.1V
		0.65V - 0.95V	20kΩ	15pF	GND	0.1V



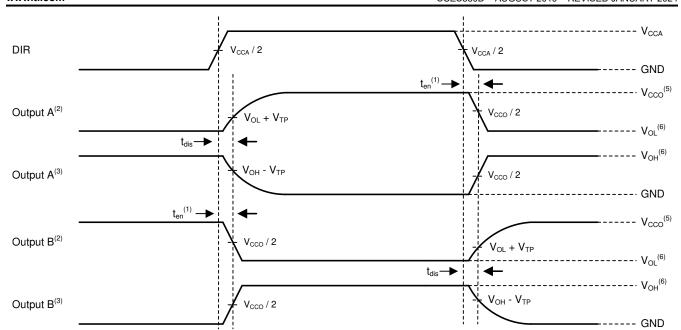
- 1. V<sub>CCI</sub> is the supply pin associated with the input port.
- 2.  $V_{OH}$  and  $V_{OL}$  are typical output voltage levels that occur with specified  $R_L$ ,  $C_L$ , and  $S_1$

Figure 6-2. Propagation Delay



- 1.  $V_{CCI}$  is the supply pin associated with the input port.
- 2.  $V_{OH}$  and  $V_{OL}$  are typical output voltage levels that occur with specified  $R_L$ ,  $C_L$ , and  $S_1$

Figure 6-3. Input Transition Rise or Fall Rate



- A. Illustrative purposes only. Enable Time is a calculation as described in the Application Information section.
- B. Output waveform on the condition that input is driven to a valid Logic Low.
- C. Output waveform on the condition that input is driven to a valid Logic High.
- D. V<sub>CCI</sub> is the supply pin associated with the input port.
- E. V<sub>CCO</sub> is the supply pin associated with the output port.
- F.  $V_{OH}$  and  $V_{OL}$  are typical output voltage levels with specified  $R_L$ ,  $C_L$ , and  $S_1$ .

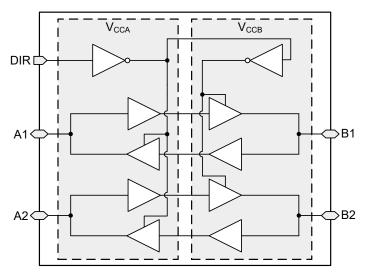
Figure 6-4. Enable Time And Disable Time

### 7 Detailed Description

### 7.1 Overview

The SN74AXC2T45 is a 2-bit, dual-supply non-inverting bidirectional voltage level translation device. Ax pins and the DIR pin are referenced to  $V_{CCA}$  logic levels, and Bx pins are referenced to  $V_{CCB}$  logic levels. The A port is able to accept I/O voltages ranging from 0.65V to 3.6V, while the B port can accept I/O voltages from 0.65V to 3.6V. A high on DIR enables data transmission from A to B and a low on DIR enables data transmission from B to A. See Section 7.4 for a summary of the operation of the control logic.

#### 7.2 Functional Block Diagram



### 7.3 Feature Description

### 7.3.1 Standard CMOS Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in Section 5.5. The worst case resistance is calculated with the maximum input voltage, given in Section 5.1, and the maximum input leakage current, given in the Section 5.5, using Ohm's law ( $R = V \div I$ ).

Signals applied to the inputs need to have fast edge rates, as defined by  $\Delta t/\Delta v$  in Section 5.3 to avoid excessive current consumption and oscillations. If a slow or noisy input signal is required, a device with a Schmitt-trigger input should be used to condition the input signal prior to the standard CMOS input.

#### 7.3.2 Balanced High-Drive CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The high drive capability of this device creates fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. The electrical and thermal limits defined in Section 5.1 must be followed at all times.

### 7.3.3 Partial Power Down (Ioff)

The inputs and outputs for this device enter a high-impedance state when the device is powered down, inhibiting current backflow into the device. The maximum leakage into or out of any input or output pin on the device is specified by I<sub>off</sub> in Section 5.5.

#### 7.3.4 V<sub>CC</sub> Isolation

The inputs and outputs for this device enter a high-impedance state when either supply is <100mV.

#### 7.3.5 Over-voltage Tolerant Inputs

Input signals to this device can be driven above the supply voltage so long as they remain below the maximum input voltage value specified in Section 5.3.

### 7.3.6 Glitch-Free Power Supply Sequencing

Either supply rail may be powered on or off in any order without producing a glitch on the I/Os (that is, where the output erroneously transitions to  $V_{CC}$  when it should be held low). Glitches of this nature can be misinterpreted by a peripheral as a valid data bit, which could trigger a false device reset of the peripheral, a false device configuration of the peripheral, or even a false data initialization by the peripheral. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report.

#### 7.3.7 Negative Clamping Diodes

The inputs and outputs to this device have negative clamping diodes as depicted in Figure 7-1.

#### **CAUTION**

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input negative voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

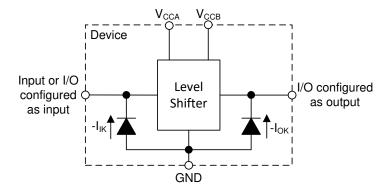


Figure 7-1. Electrical Placement of Clamping Diodes for Each Input and Output

#### 7.3.8 Fully Configurable Dual-Rail Design

Both the  $V_{CCA}$  and  $V_{CCB}$  pins can be supplied at any voltage from 0.65V to 3.6V, making the device suitable for translating between any of the voltage nodes (0.7V, 0.8V, 0.9V, 1.2V, 1.8V, 2.5V, and 3.3V).

### 7.3.9 I/Os with Integrated Static Pull-Down Resistors

To help avoid floating inputs on the I/Os, this device has  $71k\Omega$  typical integrated weak pull-downs on all data I/Os. This feature allows all inputs to be left floating without the concern for unstable outputs or increased current consumption. This also helps to reduce external component count for applications where not all channels are used or need to be fixed low. If an external pull-up is required, it should be no larger than  $7k\Omega$  to avoid contention with the  $71k\Omega$  internal pull-down.

#### 7.3.10 Supports High-Speed Translation

The SN74AXC2T45 device can support high data-rate applications. The translated signal data rate can be up to 380Mbps when the signal is translated from 1.8V to 3.3V.

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### 7.4 Device Functional Modes

Table 7-1. Function Table<sup>(1)</sup>

CONTROL INPUT	Port Status		OPERATION
DIR	A PORT	B PORT	OFERATION
L	Output (Enabled)	Input (Hi-Z)	B data to A bus
Н	Input (Hi-Z)	Output (Enabled)	A data to B bus

(1) Input circuits of the data I/O's are always active.

### 8 Application and Implementation

#### **Note**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 8.1 Application Information

The SN74AXC2T45 device can be used in level-translation applications for interfacing devices or systems operating at different interface voltages with one another. The SN74AXC2T45 device is ideal for use in applications where a push-pull driver is connected to the data I/Os. The maximum data rate can be up to 380Mbps when device translates a signal from 1.8V to 3.3V.

Figure 8-1 shows one example application where the SN74AXC2T45 device is used to translate low voltage error signals from a CPU to a higher voltage signal to properly drive the inputs of a system controller, thus alerting the system of any CPU errors such as overheating or other catastrophic processor errors.

#### 8.1.1 Enable Times

Calculate the enable times for the SN74AXC2T45 using the following formulas:

$$t_{A\_en}$$
 (DIR to A) =  $t_{dis}$  (DIR to B) +  $t_{pd}$  (B to A) (1)

$$t_{B en}$$
 (DIR to A) =  $t_{dis}$  (DIR to A) +  $t_{pd}$  (A to B) (2)

In a bidirectional application, these enable times provide the maximum delay time from the time the DIR bit is switched until an output is expected. For example, if the SN74AXC2T45 initially is transmitting from A to B, then the DIR bit is switched; the B port of the device must be disabled  $(t_{dis})$  before presenting it with an input. After the B port has been disabled, an input signal applied to it appears on the corresponding A port after the specified propagation delay  $(t_{pd})$ . To avoid bus contention care should be taken to not apply an input signal prior to the output port being disabled  $(t_{dis})$  maximum.

#### 8.2 Typical Application

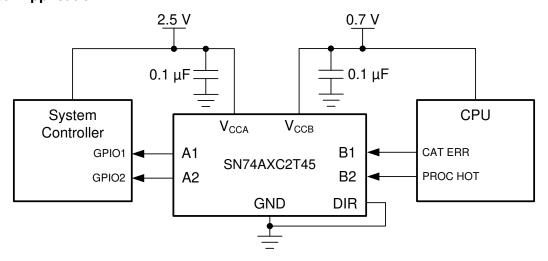


Figure 8-1. Processor Error Application



### 8.2.1 Design Requirements

For this design example, use the parameters listed in Table 8-1.

**Table 8-1. Design Parameters** 

DESIGN PARAMETERS	EXAMPLE VALUES
Input voltage range	0.65V to 3.6V
Output voltage range	0.65V to 3.6V

### 8.2.2 Detailed Design Procedure

To begin the design process, determine the following:

- · Input voltage range
  - Use the supply voltage of the device that is driving the SN74AXC2T45 device to determine the input voltage range. For a valid logic-high, the value must exceed the high-level input voltage (V<sub>IH</sub>) of the input port. For a valid logic low the value must be less than the low-level input voltage (V<sub>IL</sub>) of the input port.
- Output voltage range
  - Use the supply voltage of the device that the SN74AXC2T45 device is driving to determine the output voltage range.

### 8.2.3 Application Curve

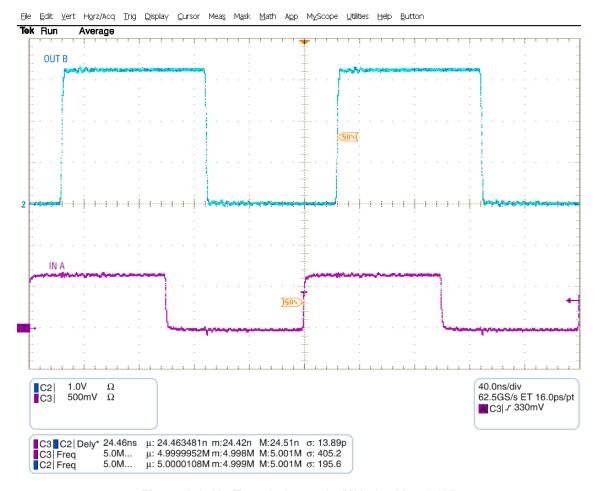


Figure 8-2. Up Translation at 2.5MHz (0.7V to 3.3V)

### 8.3 Power Supply Recommendations

Always apply a ground reference to the GND pins first. This device is designed for glitch free power sequencing without any supply sequencing requirements such as ramp order or ramp rate.

This device is designed with various power supply sequencing methods in mind to help prevent unintended triggering of downstream devices. For more information regarding the power up glitch performance of the AXC family of level translators, see the *Glitch Free Power Sequencing With AXC Level Translators* application report.

### 8.4 Layout

### 8.4.1 Layout Guidelines

For device reliability, following common printed-circuit board layout guidelines are recommended:

- Use bypass capacitors on the power supply pins and place them as close to the device as possible. A
   0.1μF capacitor is recommended, but transient performance can be improved by having both 1μF and 0.1μF
   capacitors in parallel as bypass capacitors.
- Use short trace lengths to avoid excessive loading.

### 8.4.2 Layout Example

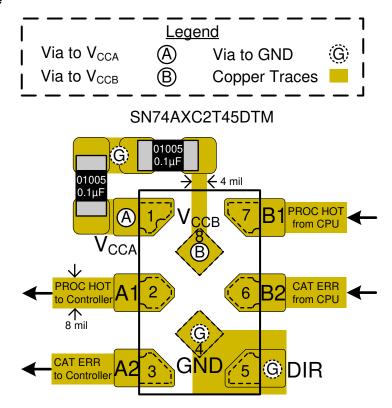


Figure 8-3. SN74AXC2T45DTM Layout Example



### 9 Device and Documentation Support

### 9.1 Documentation Support

#### 9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Implications of Slow or Floating CMOS Inputs application report
- Texas Instruments, Power Sequencing for AXC Family of Devices application report

### 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 9.4 Trademarks

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### 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision C (June 2021) to Revision D (January 2024)     Added the I/Os with Integrated Static Pull-Down Resistors section	Page18
Changes from Revision B (January 2020) to Revision C (June 2021)	Page
<ul> <li>Updated the numbering format for tables, figures, and cross-references throughout the document</li> <li>Updated the Enable Times section</li> </ul>	
Changes from Revision A (December 2019) to Revision B (January 2020)	Page

## **INSTRUMENTS** www.ti.com

Changes from Revision * (A	lugust 2019) to Revision A	(December 2019
----------------------------	----------------------------	----------------

Changed from Advance Information to Production Data ......1

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	('')	(2)			(0)	(4)	(5)		(6)
SN74AXC2T45DCTR	Active	Production	SSOP (DCT)   8	3000   LARGE T&R	Yes	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	(1H6, 2W7T) G
SN74AXC2T45DCTR.A	Active	Production	SSOP (DCT)   8	3000   LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	(1H6, 2W7T) G
SN74AXC2T45DCTRG4	Active	Production	SSOP (DCT)   8	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1H6 G
SN74AXC2T45DCTRG4.A	Active	Production	SSOP (DCT)   8	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1H6 G
SN74AXC2T45DCUR	Active	Production	VSSOP (DCU)   8	3000   LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	22HT
SN74AXC2T45DCUR.A	Active	Production	VSSOP (DCU)   8	3000   LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	22HT
SN74AXC2T45DTMR	Active	Production	X2SON (DTM)   8	5000   LARGE T&R	Yes	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	1FP
SN74AXC2T45DTMR.A	Active	Production	X2SON (DTM)   8	5000   LARGE T&R	Yes	NIPDAUAG	Level-1-260C-UNLIM	-40 to 125	1FP

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



## **PACKAGE OPTION ADDENDUM**

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#### OTHER QUALIFIED VERSIONS OF SN74AXC2T45:

Automotive: SN74AXC2T45-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

## **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

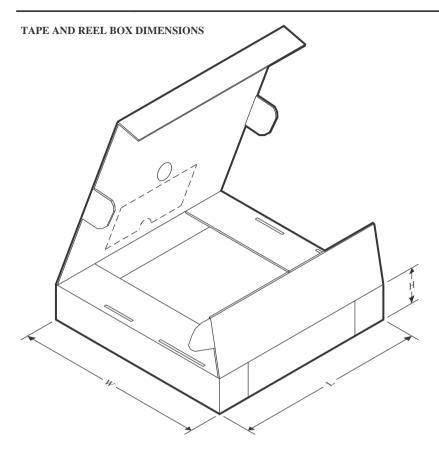


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AXC2T45DCTR	SSOP	DCT	8	3000	180.0	12.4	3.15	4.35	1.55	4.0	12.0	Q3
SN74AXC2T45DCTR	SSOP	DCT	8	3000	177.8	12.4	3.45	4.4	1.45	4.0	12.0	Q3
SN74AXC2T45DCTRG4	SSOP	DCT	8	3000	177.8	12.4	3.45	4.4	1.45	4.0	12.0	Q3
SN74AXC2T45DCUR	VSSOP	DCU	8	3000	178.0	9.0	2.25	3.35	1.05	4.0	8.0	Q3
SN74AXC2T45DTMR	X2SON	DTM	8	5000	180.0	9.5	0.93	1.49	0.43	2.0	8.0	Q1
SN74AXC2T45DTMR	X2SON	DTM	8	5000	178.0	8.4	0.93	1.49	0.43	2.0	8.0	Q1



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### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AXC2T45DCTR	SSOP	DCT	8	3000	190.0	190.0	30.0
SN74AXC2T45DCTR	SSOP	DCT	8	3000	183.0	183.0	20.0
SN74AXC2T45DCTRG4	SSOP	DCT	8	3000	183.0	183.0	20.0
SN74AXC2T45DCUR	VSSOP	DCU	8	3000	180.0	180.0	18.0
SN74AXC2T45DTMR	X2SON	DTM	8	5000	189.0	185.0	36.0
SN74AXC2T45DTMR	X2SON	DTM	8	5000	205.0	200.0	33.0





#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-187 variation CA.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.







#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





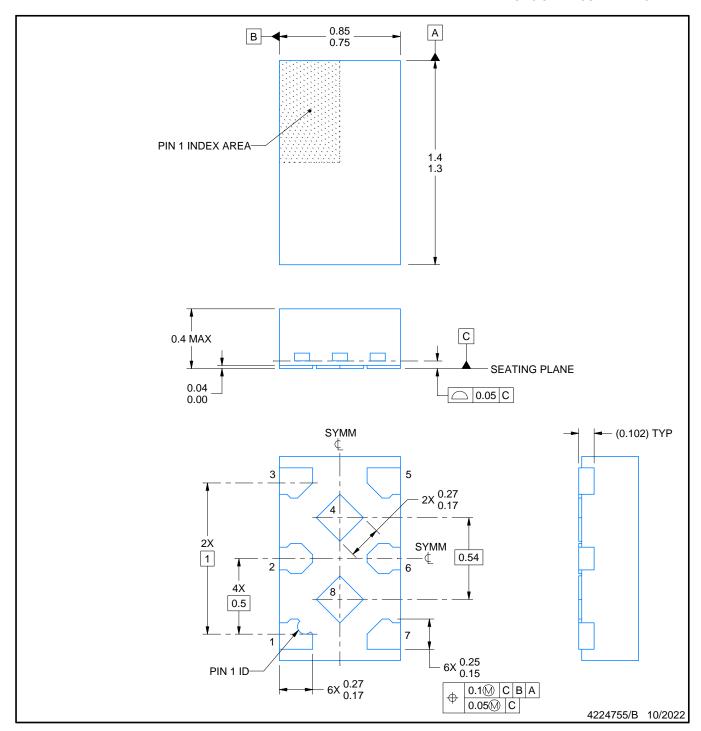
NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





PLASTIC SMALL OUTLINE - NO LEAD

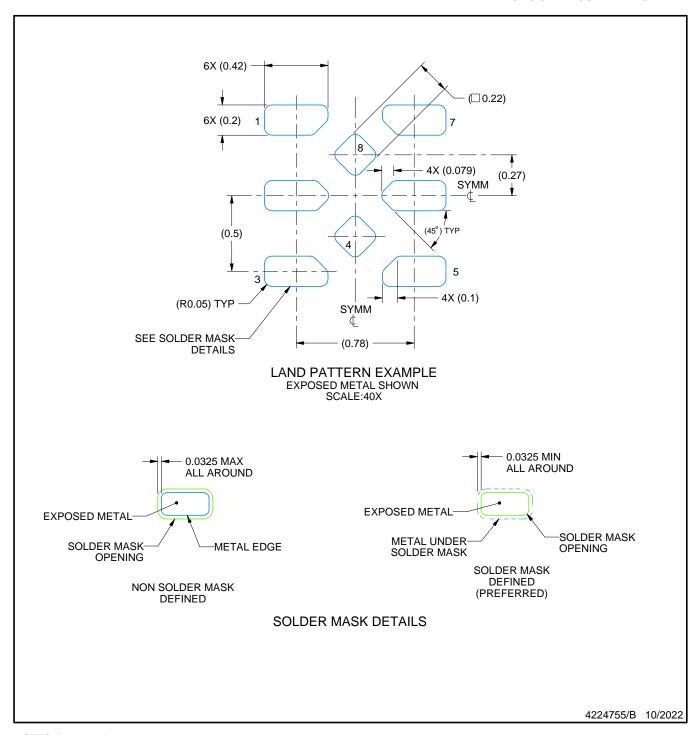


### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
- 3. The package thermal pad(s) must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC SMALL OUTLINE - NO LEAD

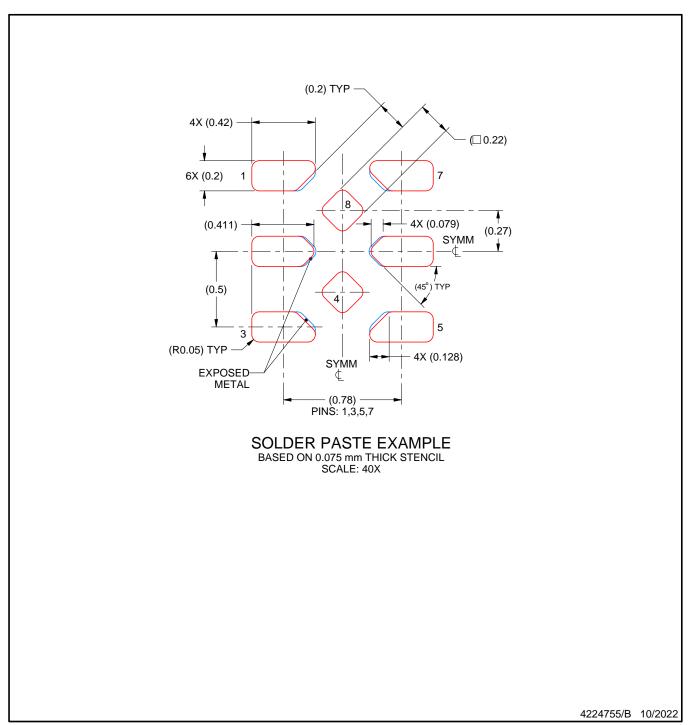


NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC SMALL OUTLINE - NO LEAD



5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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